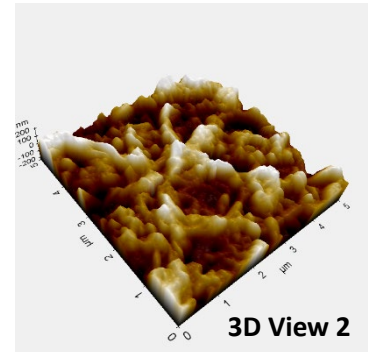
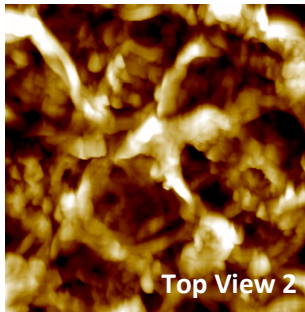
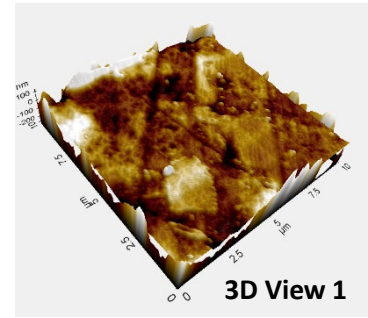
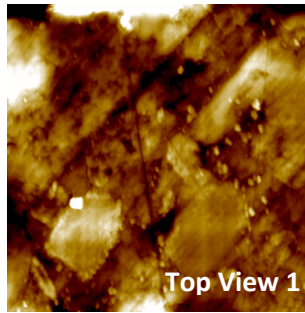
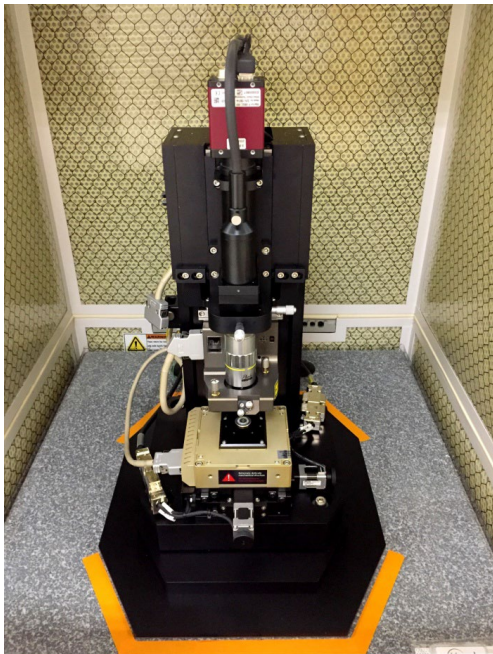


## Atomic Force Microscope (AFM)



AFM is an extremely precise microscope that images a sample by rapidly moving a probe with a nanometer-sized tip across its surface. The AFM system can be operated in contact mode and non-contact mode.

AFM can make measurements in three dimensions,  $x$ ,  $y$ , and  $z$  (normal to the sample surface), thus enabling the presentation of three-dimensional images of a sample surface. Quantitative measurement such as surface roughness and adhesion force can be performed on AFM.

AFM requires neither a vacuum environment nor any special sample preparation, and they can be used in either an ambient or liquid environment.

**Brand – Park Systems; Model – XE100**

**For enquiries, please contact the staff in-charge: Ms Maria Chong**

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